Abstracts

S-parameter broad-band measurements on-microstrip and fast extraction of the substrate intrinsic properties

J. Hinojosa. "S-parameter broad-band measurements on-microstrip and fast extraction of the substrate intrinsic properties." 2001 Microwave and Wireless Components Letters 11.7 (Jul. 2001 [MWCL]): 305-307.

A broad-band technique for determining the electromagnetic properties of isotropic film-shaped materials, which uses a microstrip line, is presented. Complex permittivity and permeability are computed from analytical equations and S-parameter measurements of microstrip cells propagating the dominant mode. Measured /spl epsiv//sub r/ and /spl mu//sub r/ data for several materials are presented between 0.05 GHz and 40 GHz. This technique shows a good agreement between measured and predicted data.

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